

<b>INFORMATION DISCLOSURE CITATION</b> <small>(Use several sheets if necessary)</small>				ATTY DOCKET NO. <b>TROLOGY 02.02</b>		APPLICATION NO. <b>10/536,576</b>	
				APPLICANT(S) <b>Szwaykowski et al.</b>			
				FILING DATE <b>February 6, 2006</b>		GROUP ART UNIT	
<b>U.S. PATENT DOCUMENTS</b>							
*EXAMINER INITIAL		DOCUMENT NUMBER <i>SEARCHED &amp; INDEXED DEC 17 2007</i>	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		4,583,855	04.22.1986	Bareket	356	351	
		6,304,330	10.16.2001	Millerd et al.	356	521	
		6,552,808	04.22.2003	Millerd et al.	356	521	
		3,950,103	04.13.1976	Schmidt			
		6,128,080	10/2000	Janik et al.			
<b>U.S. PATENT APPLICATION PUBLICATIONS</b>							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		2003/0095264	05/2003	Ruchet	356	491	
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
		DE 196 52 113	18.06.1998	Germany			YES
		WO 2004/051182	17.06.2004	PCT	G01B	9/02	NO
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
		<b>Hettwer, et al., "Three Channel Phase-Shifting Interferometer Using Polarization-Optics and a Diffraction Grating", The International Society for Optical Engineering, Optical Engineering, Vol. 39, pps. 960-966, April 2000 (abstract only).</b>					
		<b>Nakadate et al., "Real-Time Fringe Patter Processing and its Applications", Proc. of SPIE, Vol. 2544, pps. 74-86, June 1995 (abstract only).</b>					
EXAMINER				DATE CONSIDERED			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

**INFORMATION DISCLOSURE CITATION**  
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**U.S. PATENT DOCUMENTS**

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

**OTHER DOCUMENTS** *(Including Author, Title, Date, Pertinent Pages, Etc.)*

		Sivakumar, et al., "Large Surface Profile Measurement with Instantaneous Phase-Shifting Interferometry", Optical Engineering, February 2003, Vol. 42, Issue 2, pps. 367-372 (abstract only).
		Koliopoulos, Chris L., "Simultaneous Phase-Shift Interferometer", Proceedings of SPIE, Vol. 1531, Advanced Optical Manufacturing and Testing II, 1992, pps. 119-127.

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